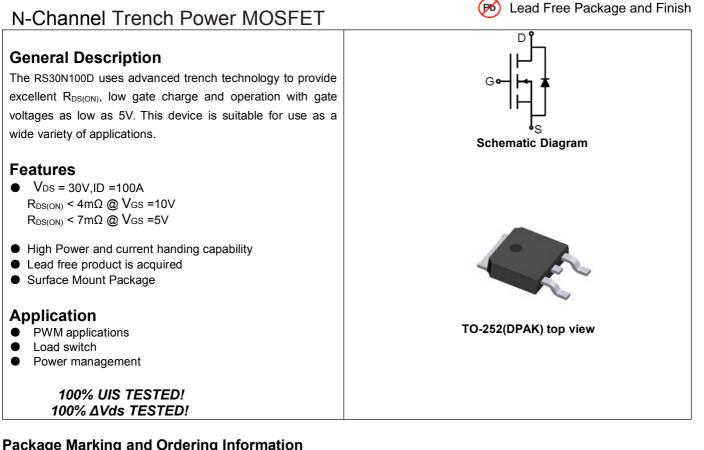


RS30N100D



I dekage marking	and ordering	Information			
Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
RS30N100D	RS30N100D	TO-252	325mm	16mm	2500

Table 1. Absolute Maximum Ratings (T_A=25℃)

Symbol	Parameter	Value	Unit
Vds	Drain-Source Voltage (VGS=0V)	30	V
Vgs	Gate-Source Voltage (VDs=0V)	±20	V
1	Drain Current-Continuous(Tc=25 [°] C)	100	А
ID	Drain Current-Continuous(Tc=100°C)	70	A
DM (pluse)	Drain Current-Continuous@ Current-Pulsed (Note 1)	400	A
Р	Maximum Power Dissipation(Tc=25°C)	88	W
PD	Maximum Power Dissipation(Tc=100°C)	44	W
Eas	Avalanche energy (Note 2)	320	mJ
T _J ,T _{STG}	Operating Junction and Storage Temperature Range	-55 To 175	°C

Notes 2.EAs condition: $T_J=25^{\circ}$, VDD=20V, VG=10V, RG=25 Ω

Table 2. Thermal Characteristic

Symbol	Parameter	Тур	Max	Unit
Rejc	Thermal Resistance, Junction-to-Case	-	1.7	°C/W



Symbol	Electrical Characteristics (TA=2 Parameter	Conditions	Min	Тур	Max	Unit
On/Off Sta	tes					
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V I _D =250µA	30			V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} =30V,V _{GS} =0V			1	μA
I _{GSS}	Gate-Body Leakage Current	V _{GS} =±20V,V _{DS} =0V			±100	nA
$V_{\text{GS(th)}}$	Gate Threshold Voltage	V _{DS} =V _{GS} ,I _D =250µA	1	1.5	2.5	V
g fs	Forward Transconductance	V _{DS} =5V,I _D =15A		30		S
R _{DS(ON)}	Drain-Source On-State Resistance	V _{GS} =10V, I _D =20A		3.1	4	mΩ
TOS(ON)		V _{GS} =5V, I _D =15A		4.2	7	mΩ
Dynamic C	Characteristics					
Ciss	Input Capacitance			2600		pF
Coss	Output Capacitance	V _{DS} =15V,V _{GS} =0V, f=1.0MHz		412		pF
Crss	Reverse Transfer Capacitance			300		pF
Rg	Gate resistance	V _{GS} =0V, V _{DS} =0V,f=1.0MHz		3.3		Ω
Switching	Times		-			
t _{d(on)}	Turn-on Delay Time			13		nS
tr	Turn-on Rise Time	VGS=10V, VDS=15V,		16		nS
t _{d(off)}	Turn-Off Delay Time			40		nS
t _f	Turn-Off Fall Time			14		nS
Qg	Total Gate Charge			58		nC
Q_{gs}	Gate-Source Charge	Vgs=10V, Vds=15V, Id=14A		7		nC
Q_{gd}	Gate-Drain Charge			18		nC
Source-Dr	ain Diode Characteristics					-
Isd	Source-Drain Current(Body Diode)				100	A
V _{SD}	Forward on Voltage ^(Note 1)	Vgs=0V,Is=20A			1.2	V

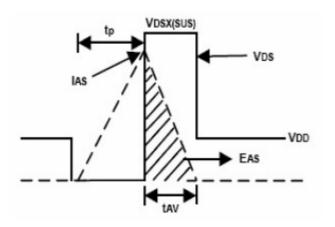
Table 3. Electrical Characteristics (TA=25°C unless otherwise noted)

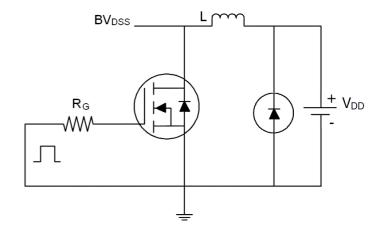
Notes 1. Repetitive Rating: Pulse width limited by maximum junction temperature.



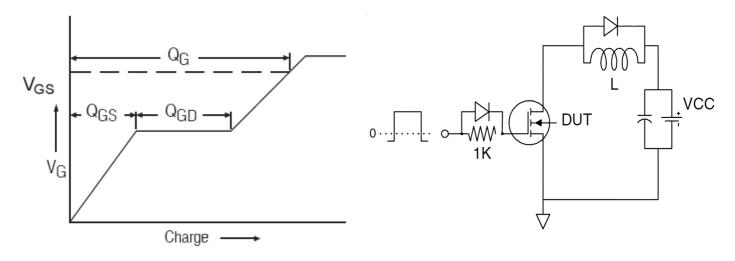
Test Circuit

1) E_{AS} Test Circuits

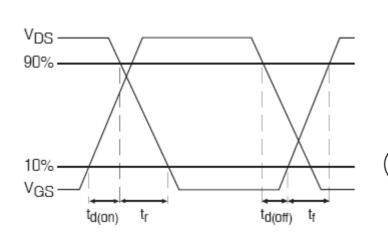


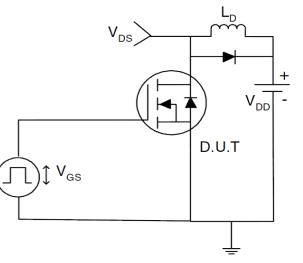


2) Gate Charge Test Circuit:











TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS (Curves)

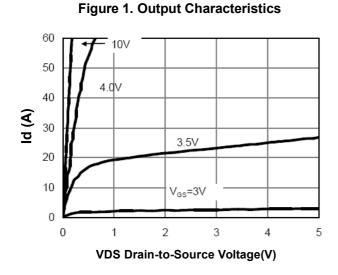


Figure 3. Max BV_{DSS} vs Junction Temperature

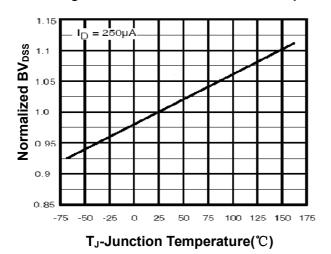
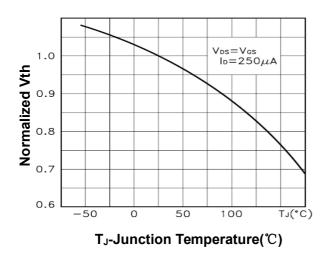
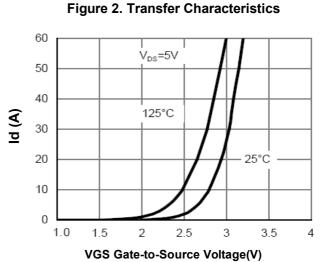
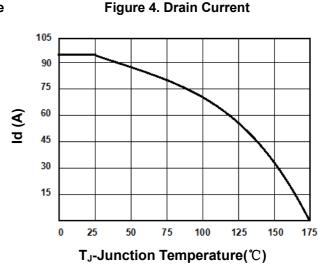


Figure 5. V_{GS(th)} vs Junction Temperature







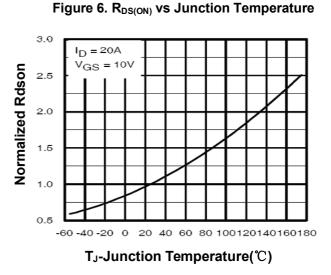
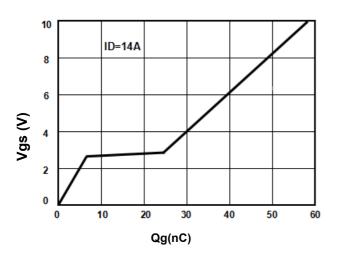




Figure 7. Gate Charge Waveforms



RS30N100D



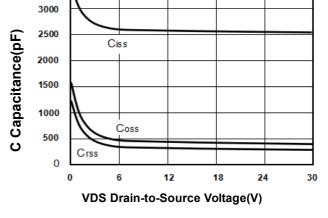


Figure 9. Body-Diode Characteristics

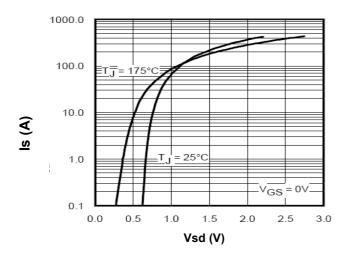
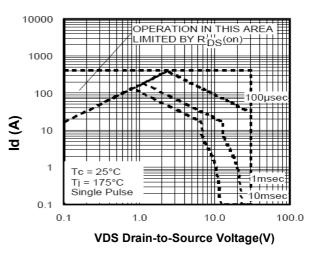
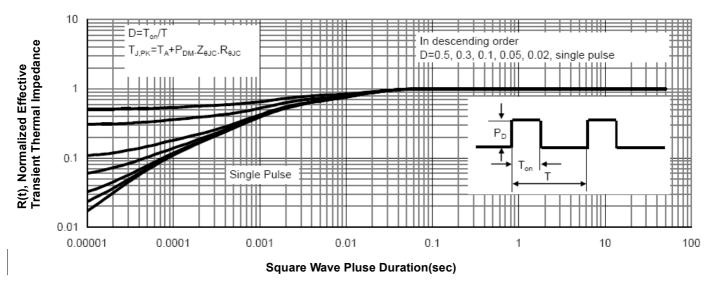


Figure 10. Maximum Safe Operating Area



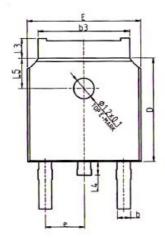


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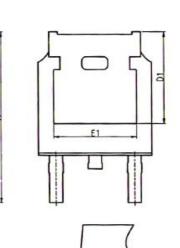
TO-252 Package Information



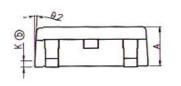
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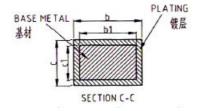
C

4



0	COMMON L	DIMENSIO	NS	
	mm			
SYMBOL	MIN	NOM	MAX	
A	2.20	2.30	2.38	
Al	0.00	-	0.10	
A2	0.97	1.07	1.17	
b	0.72	0.78	0.85	
b1	0.71	0.76	0.81	
b3	5.23	5.33	5.46	
c	0.47	0.53	0.58	
cl	0.46	0.51	0.56	
D	6.00	6.10	6.20	
D1		5. 30REF		
E	6.50	6.60	6.70	
EI	4.70	4.83	4.92	
e		2. 286BSC		
н	9,90	10.10	10.30	
L	1.40	1.50	1.70	
LI		2. 90REF		
L2		0, 51BSC		
L3	0.90		1.25	
11	0.60	0.80	1.00	
L5_	1.70	1.80	1.90	
θ	0*	-	8*	
01	5*	7.	9.	
02	5*	7*	9*	
ĸ		0. 10REF		





NOTES 1.ALL DIMENSIONS REFER TO JEDEC STANDARD TO-252 AA, DO NOT INCLUDE MOLD FLASH OR PROTRUSIONS.

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